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Advance Information

Nine-Wide Buffers

High-Performance Silicon-Gate CMOS

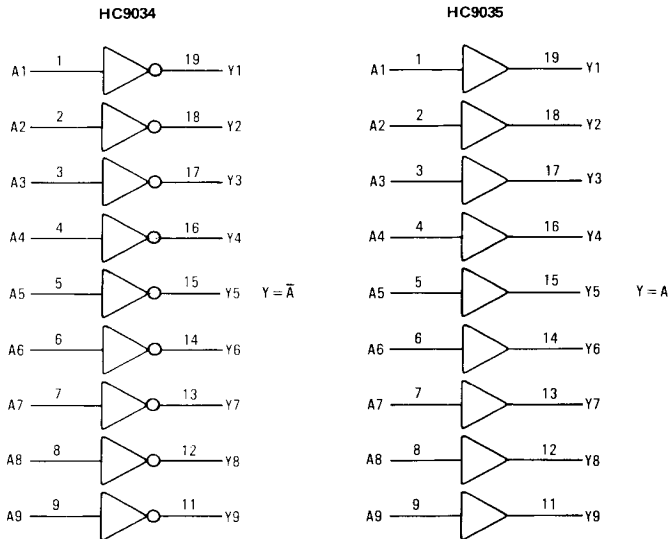
The MC54/74HC9034 consists of nine inverting buffers and the MC54/74HC9035 consists of nine noninverting buffers. Both devices have inputs that are compatible with standard CMOS outputs; with pullup resistors, they are compatible with LSTTL outputs.

These devices find primary use as interfaces between microprocessors and peripheral hardware such as keyboards, memory arrays, displays, etc. They are especially useful when 8 bits of data are needed and an extra bit is required for parity, control, or handshake.

Using 9-Wide buffers, instead of standard hex buffers, decreases component count and increases system reliability.

- Output Drive Capability: 10 LSTTL Loads
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 2 to 6 V
- Low Input Current: 1 μ A
- High Noise Immunity Characteristic of CMOS Devices
- In Compliance with the Requirements Defined by JEDEC Standard No. 7A
- Chip Complexity: 54 FETs or 13.5 Equivalent Gates (HC9034)
 72 FETs or 18 Equivalent Gates (HC9035)

LOGIC DIAGRAMS



PIN 20 = V_{CC}
 PIN 10 = GND

MC54/74HC9034
MC54/74HC9035

J SUFFIX CERAMIC CASE 732

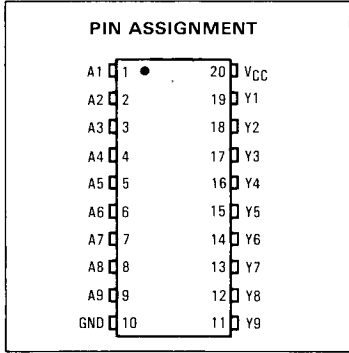
N SUFFIX PLASTIC CASE 738

DW SUFFIX SOIC CASE 751D

ORDERING INFORMATION

MC74HCXXXXN	Plastic
MC54HCXXXXJ	Ceramic
MC74HCXXXXDW	SOIC

T_A = -55° to 125°C for all packages.
 Dimensions in Chapter 7.



FUNCTION TABLE

A Input	Y Outputs	
	HC9034	HC9035
L	H	L
H	L	H

This document contains information on a new product. Specifications and information herein are subject to change without notice.

MC54/74HC9034•MC54/74HC9035

MAXIMUM RATINGS*

Symbol	Parameter	Value	Unit
V _{CC}	DC Supply Voltage (Referenced to GND)	-0.5 to +7.0	V
V _{in}	DC Input Voltage (Referenced to GND)	-1.5 to V _{CC} + 1.5	V
V _{out}	DC Output Voltage (Referenced to GND)	-0.5 to V _{CC} + 0.5	V
I _{in}	DC Input Current, per Pin	±20	mA
I _{out}	DC Output Current, per Pin	±25	mA
I _{CC}	DC Supply Current, V _{CC} and GND Pins	±75	mA
P _D	Power Dissipation in Still Air, Plastic or Ceramic DIP† SOIC Package†	750 500	mW
T _{stg}	Storage Temperature	-65 to +150	°C
T _L	Lead Temperature, 1 mm from Case for 10 Seconds (Plastic DIP or SOIC Package) (Ceramic DIP)	260 300	°C

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range GND ≤ (V_{in} or V_{out}) ≤ V_{CC}. Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

*Maximum Ratings are those values beyond which damage to the device may occur. Functional operation should be restricted to the Recommended Operating Conditions.

†Derating — Plastic DIP: -10 mW/°C from 65° to 125°C
Ceramic DIP: -10 mW/°C from 100° to 125°C
SOIC Package: -7 mW/°C from 65° to 125°C

For high frequency or heavy load considerations, see Chapter 4 subject listing on page 4-2.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V _{CC}	DC Supply Voltage (Referenced to GND)	2.0	6.0	V
V _{in} , V _{out}	DC Input Voltage, Output Voltage (Referenced to GND)	0	V _{CC}	V
T _A	Operating Temperature, All Package Types	-55	+125	°C
t _r , t _f	Input Rise and Fall Time (Figure 1)	V _{CC} = 2.0 V V _{CC} = 4.5 V V _{CC} = 6.0 V	0 1000 500 400	ns

DC ELECTRICAL CHARACTERISTICS (Voltages Referenced to GND)

Symbol	Parameter	Test Conditions	V _{CC} V	Guaranteed Limit			Unit
				25°C to -55°C	≤ 85°C	≤ 125°C	
V _{IH}	Minimum High-Level Input Voltage	V _{out} = 0.1 V or V _{CC} - 0.1 V I _{out} ≤ 20 μA	2.0	1.5	1.5	1.5	V
			4.5	3.15	3.15	3.15	
			6.0	4.2	4.2	4.2	
V _{IL}	Maximum Low-Level Input Voltage	V _{out} = 0.1 V or V _{CC} - 0.1 V I _{out} ≤ 20 μA	2.0	0.3	0.3	0.3	V
			4.5	0.9	0.9	0.9	
			6.0	1.2	1.2	1.2	
V _{OH}	Minimum High-Level Output Voltage	V _{in} = V _{IH} or V _{IL} I _{out} ≤ 20 μA	2.0	1.9	1.9	1.9	V
			4.5	4.4	4.4	4.4	
			6.0	5.9	5.9	5.9	
V _{OL}	Maximum Low-Level Output Voltage	V _{in} = V _{IH} or V _{IL} I _{out} ≤ 20 μA	2.0	0.1	0.1	0.1	V
			4.5	0.1	0.1	0.1	
			6.0	0.1	0.1	0.1	
I _{in}	Maximum Input Leakage Current	V _{in} = V _{IH} or V _{IL} I _{out} ≤ 4.0 mA I _{out} ≤ 5.2 mA	2.0	0.26	0.33	0.40	μA
			4.5	0.26	0.33	0.40	
			6.0	0.26	0.33	0.40	
I _{in}	Maximum Input Leakage Current	V _{in} = V _{CC} or GND	6.0	±0.1	±1.0	±1.0	μA
I _{CC}	Maximum Quiescent Supply Current (per Package)	V _{in} = V _{CC} or GND I _{out} = 0 μA	6.0	2	20	40	μA

NOTE: Information on typical parametric values can be found in Chapter 4 subject listing on page 4-2.

MOTOROLA HIGH-SPEED CMOS LOGIC DATA

5-650

MC54/74HC9034 • MC54/74HC9035

AC ELECTRICAL CHARACTERISTICS ($C_L \geq 50$ pF, Input $t_r = t_f = 6$ ns)

Symbol	Parameter	VCC V	Guaranteed Limit			Unit
			25°C to -55°C	≤ 85°C	≤ 125°C	
t_{PLH} , t_{PHL}	Maximum Propagation Delay, Input A to Output Y (Figures 1 and 2)	HC9034	2.0	80	100	120
			4.5	16	20	24
			6.0	14	17	20
		HC9035	2.0	90	115	135
			4.5	18	23	27
			6.0	15	20	23
t_{TLH} , t_{THL}	Maximum Output Transition Time, Any Output (Figures 1 and 2)	2.0	75	95	110	
		4.5	15	19	22	
		6.0	13	16	19	
C_{in}	Maximum Input Capacitance	—	10	10	10	pF

NOTES:

1. For propagation delays with loads other than 50 pF, see Chapter 4 subject listing on page 4-2.
2. Information on typical parametric values can be found in Chapter 4.

C_{PD}	Power Dissipation Capacitance (Per Buffer) Used to determine the no-load dynamic power consumption: $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$ For load considerations, see Chapter 4 subject listing on page 4-2.	Typical @ 25°C, $V_{CC} = 5.0$ V	pF
		30	

SWITCHING WAVEFORMS

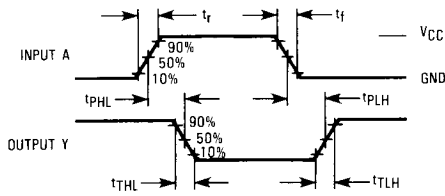


Figure 1A. HC9034

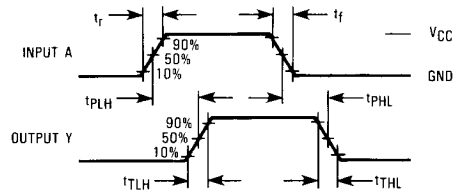
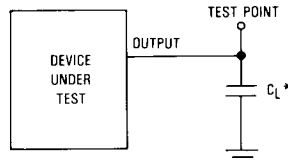


Figure 1B. HC9035



*Includes all probe and jig capacitance.

Figure 2. Test Circuit

EXPANDED LOGIC DIAGRAMS (1/9 of the Device)

